

Notice of References Cited

Application No.

09/14/964

Applicant

Marino et al.

Examiner

Harold Winhamer

Group Art Unit

2857

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U.S. PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
X	U	Bendat et al., "Engineering Applications of Correlation and Spectral Analysis," second edition, John Wiley & Sons, pages 70-77.	1993 (no month)
X	V	Hayes, "Statistical Digital Signal Processing and Modeling," first edition, John Wiley & Sons, pages 128-203, 492-555.	1996 (no month)
X	W	Evaluation Engineering, Rorden Christensen, Eight Products, With Honors From Rorden, 3 pages	1999 (no month)
X	X	Heart Conference Meritorious Paper Award, Parkemi et al., 8 pages.	3/99

* A copy of this reference is not being furnished with this Office action.
(See Manual of Patent Examining Procedure, Section 707.05(a).)

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Application No.

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X	V	Ambient Cancellation / Source Localization CASPER, product literature, 12 pages	2000 (no month)
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